AAEON Technology INC.
ISO-9001/ISO-14001 Certified
Industrial Automation PCs

SBC-659
Temperature Test Report

Issued by:		/	*04/15/2002*
	Rex Chang **QE Engineer**		**Date**
Reviewed by:		/	*04/15/2002*
	Wen - Yuan Yang **QE Manager**		**Date**

1.Test Product: Half-size CPU Card

2. Model Name: SBC-659 REV.A1.0

3. Test Date: 04-11-2002

4. Test Site: AAEON QA Internal Lab.

5. Test Equipment

Type	MFR	Model Number	Serial Number	Last CAL.
Programmable Temperature & Humidity Chamber	KSON	THS-D4L+-100	1241	06/10/01
Programmable Temperature & Humidity Chamber	KSON	TS-F3L+-100	1467	04/10/01

6. Test Standard :

NO.	Description
IEC 68-2-30	Test DB : Damp Heat Test

7. Testing Item:
Test Temperature & Humidity Power On/Off Test
Test Temperature Power On/Off Test

8. Additional Test Peripheral:

Configuration	Model
Test Fixture	Power on/off (110V) Fixture

9. Test Environment:
Temperature: 20 ±2℃
Humidity: 60 ±20%RH

10. Sample Configuration & Quantity Under Test:
Quantity: 2
Sample Configuration:
Sample 1 (Temperature & Humidity Power On/Off Test)

CPU	Intel PentiumIII 1GHz (100x10 ; 1.75V)
DRAM	SO-DIMM 256MB HITACHI 5225165BTT75 (PC-133 SDRAM)
System BIOS Version	SBC-659 BIOS Rev.1.3
Chipset	Intel 815E
VGA Chipset	Intel 815E Share system memory up to 4MB(MAX)
I/O Chipset	ITE-8712 Fully 16 bit I/O decoded.
Cooler (P/N)	1759200316

Sample 2 (Test Temperature Power On/Off Test)

CPU	Intel PentiumIII 1GHz (133x7.5 ; 1.7V)
DRAM	SO-DIMM 256MB SAMSUNG K4S560832B-TC75 (PC-133 SDRAM)
System BIOS Version	SBC-659 BIOS Rev.1.3
Chipset	Intel 815E
VGA Chipset	Intel 815E Share system memory up to 4MB(MAX)
I/O Chipset	ITE-8712 Fully 16 bit I/O decoded.
Cooler (P/N)	1759200316

Cooler (P/N): 1759200316

11. Test Result:

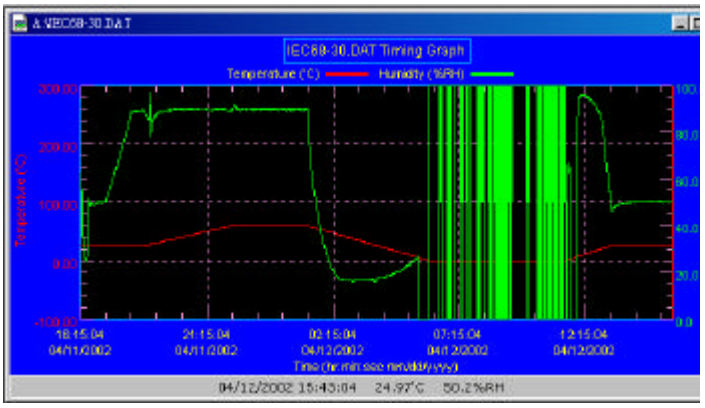
Standard	Description	Result
IEC 68-2-30	Temperature & Humidity Power On/Off Test	Pass
IEC 68-2-30	Temperature Power On/Off Test	Pass

12. Temperature & Humidity Power On/Off Test

12-1 Testing Specification:

Step	Temperature (℃)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

12-2 Test Curve:

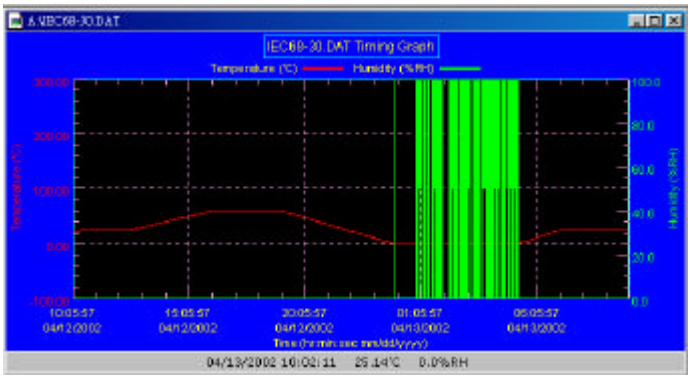


13. Temperature Power On/Off Test

13-1 Testing Specification:

Step	Temperature (℃)	Humidity (%RH)	Duration (HH:MM)
1	25	–	00:30
2	25	–	00:30
3	25	–	01:00
4	25	–	00:30
5	60	–	03:30
6	60	–	03:00
7	0	–	04:50
8	0	–	05:23
9	25	–	01:47
10	25	–	03:00

13-2 Test Curve:



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SBC-659

Dynamic Test

Temperature / Humidity Test Report

Issued by:		/	*04/15/2002*
	Rex Chang **QE Engineer**		**Date**
Reviewed by:		/	*04/15/2002*
	Wen - Yuan Yang **QE Manager**		**Date**

1.Test Product: Half-size CPU Card

2. Model Name: SBC-659 REV.A1.0

3. Test Date: 04-13-2002

4. Test Site: AAEON QA Internal Lab.

5. Test Equipment

Type	MFR	Model Number	Serial Number	Last CAL.
Programmable Temperature & Humidity Chamber	KSON	THS-D4L+-100	1241	06/10/01

6. Test Standard :

NO.	Description
IEC 68-2-61	Test Z/ABD : Climatic Sequence Test

7. Testing Item:
Temperature & Humidity Dynamic Test

8. Additional Test Peripheral:

Configuration	Model
Test Software	QAPlus 5.5

8. Test Environment:
Temperature: 20 ±2℃
Humidity: 60 ±20%RH

9. Sample Configuration & Quantity Under Test:
Quantity: 1
Sample Configuration:

CPU	Intel PentiumIII 1GHz (100x10 ; 1.75V)
DRAM	SO-DIMM 256MB HITACHI 5225165BTT75 (PC-133 SDRAM)
System BIOS Version	SBC-659 BIOS Rev.1.3
Chipset	Intel 815E
VGA Chipset	Intel 815E Share system memory up to 4MB(MAX)
I/O Chipset	ITE-8712 Fully 16 bit I/O decoded.
Cooler (P/N)	1759200316

Cooler (P/N): 1759200316

10. Test Result:

Standard	Description	Result
IEC 68-2-61	Temperature & Humidity Dynamic Test (Run QAPlus 5.5)	Pass

11. Temperature & Humidity Dynamic Test:

11-1 Testing Specification:

Step	Temperature (℃)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	60	30	01:10
4	60	30	03:20
5	25	50	01:10
6	25	50	00:50
7	25	90	03:30
8	25	90	01:00
9	60	90	03:53
10	60	90	04:07
11	25	90	03:53
12	25	50	04:07
13	25	50	03:30
14	25	50	00:30
15	0	0	02:30
16	0	0	10:30
17	25	50	02:30
18	25	50	00:30

11-2 Test Curve: